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P/4178-10

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of  
Yusuke MURAOKA et al.  
Serial No.: 10/700,020  
Filed: November 3, 2003

New York, New York  
Date: May 27, 2004  
Group Art Unit: --  
Examiner: --

For: SUBSTRATE PROCESSING METHOD, SUBSTRATE PROCESSING APPARATUS  
AND SUBSTRATE PROCESSING SYSTEM

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

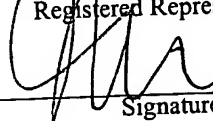
Sir:

Further to the Submission dated January 23, 2004, attached hereto please find a corrected Form PTO-1449. The Examiner is requested to sign and return this form, instead of the form that was filed January 23, 2004.

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents P.O. Box 1450, Alexandria, VA 22313-1450, on May 27, 2004

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Name of applicant, assignee or  
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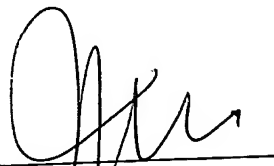


Signature

May 27, 2004

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Respectfully submitted,



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APPLICANT'S ART CITATION  
(Use several sheets if necessary)

Application 10/700,020

OFGS File No. P/4178-10

Applicant  
Yusuke MURAOKA et al.

Filing Date  
November 3, 2003

Group Art Unit \_\_\_

### U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date MM-YYYY	Name	Class	Sub-class	Filing Date If Appropriate
	US-5,700,379	12-1997	Biebl	216	2	
	US-6,358,673	03-2002	Namatsu	430	311	
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### FOREIGN PATENT DOCUMENTS

	Document Number	Date MM-YYYY	Country	Class	Sub-class	Translation	
						Yes	No
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	8-250464	09-1996	Japan				x
	EP 0 732 557 A2	09-1996	EP				
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	2002-329650	11-2002	JP				x
	2003-51475	02-2003	JP				x

### OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

	A Concise Explanation sheet

Examiner

Date Considered

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.